

<b>Notice of References Cited</b>	Application/Control No. 09/836,397		Applicant(s)/Patent Under Reexamination CHAN, HARK C.	
	Examiner SARGON N. NANO		Art Unit 2457	Page 1 of 1

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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